

Notice of References Cited	Application/Control No. 10/533,564	Applicant(s)/Patent Under Reexamination IWASAKI	
	Examiner Michael P. Mooney	Art Unit 2883	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,573,984	06-2003	Jung et al.	356/73
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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